

# **AONS66609T**

60V N-Channel AlphaSGT™

## **General Description**

- AlphaSGT<sup>TM</sup> N-Channel Power MOSFET
- Low R<sub>DS(ON)</sub>
- Low Gate Charge
- Enhanced body diode performance.
- RoHS 2.0 and Halogen-Free Compliant

## **Applications**

- Motor and BMS
- Synchronous Rectification in DC/DC and AC/DC Converters.

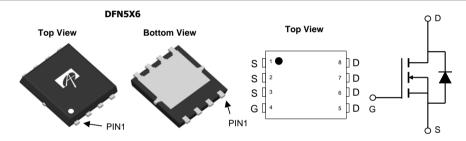
## **Product Summary**

 $\begin{array}{ll} V_{DS} & 60V \\ I_{D} \; (at \; V_{GS} \! = \! 10V) & 313A \\ R_{DS(ON)} \; (at \; V_{GS} \! = \! 10V) & < 1.25 m\Omega \\ R_{DS(ON)} \; (at \; V_{GS} \! = \! 8V) & < 1.4 m\Omega \end{array}$ 

100% UIS Tested 100% Rg Tested

Max Tj=175°C





Orderable Part Number Package Type		Form	Minimum Order Quantity
AONS66609T	DFN 5x6	Tape & Reel	3000

Parameter		Symbol	Maximum	Units	
Drain-Source Voltage Gate-Source Voltage		V <sub>DS</sub>	60	V	
		$V_{GS}$	±20	V	
Continuous Drain	T <sub>C</sub> =25°C	1-	313	A	
Current	T <sub>C</sub> =100°C	I <sub>D</sub>	221		
Pulsed Drain Current <sup>C</sup>		I <sub>DM</sub>	880		
Continuous Drain	T <sub>A</sub> =25°C	1	53	А	
Current	T <sub>A</sub> =70°C	IDSM	44	^	
Avalanche Current <sup>C</sup>		I <sub>AS</sub>	60	A	
Avalanche energy	L=0.3mH	E <sub>AS</sub>	540	mJ	
	T <sub>C</sub> =25°C	Ь	258	W	
Power Dissipation <sup>B</sup>	T <sub>C</sub> =100°C	P <sub>D</sub>	129	VV	
	T <sub>A</sub> =25°C	В	7.5	W	
Power Dissipation <sup>A</sup> T <sub>A</sub> =70°C		P <sub>DSM</sub>	5.2	¬	
Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>STG</sub>	-55 to 175	°C	

Thermal Characteristics						
Parameter		Symbol	Тур	Max	Units	
Maximum Junction-to-Ambient A	t ≤ 10s	D	15	20	°C/W	
Maximum Junction-to-Ambient AD	Steady-State	$R_{\theta JA}$	40	50	°C/W	
Maximum Junction-to-Case	Steady-State	$R_{\theta JC}$	0.43	0.58	°C/W	



#### Electrical Characteristics (T<sub>J</sub>=25°C unless otherwise noted)

Symbol	Parameter	Conditions		Min	Тур	Max	Units
STATIC F	PARAMETERS						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$I_D=250\mu A, V_{GS}=0V$		60			V
I <sub>DSS</sub> Zero Gate	Zero Gate Voltage Drain Current	$V_{DS}$ =60V, $V_{GS}$ =0V				1	μA
	Zelo Gale Vollage Dialii Current		T <sub>J</sub> =55°C			5	μΑ
I <sub>GSS</sub>	Gate-Body leakage current	$V_{DS}$ =0V, $V_{GS}$ =±20V				±100	nA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$ , $I_{D}=250\mu A$		2.1	2.7	3.3	V
		$V_{GS}$ =10V, $I_D$ =20A			1	1.25	mΩ
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance		T <sub>J</sub> =125°C		1.7	2.1	11152
		$V_{GS}$ =8V, $I_D$ =20A			1.1	1.4	mΩ
g <sub>FS</sub>	Forward Transconductance	$V_{DS}$ =5V, $I_D$ =20A			90		S
$V_{SD}$	Diode Forward Voltage	I <sub>S</sub> =1A, V <sub>GS</sub> =0V			0.7	1	V
Is	Maximum Body-Diode Continuous Curr	rent			200	Α	
DYNAMI	CPARAMETERS						
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =30V, f=1MHz			6350		pF
Coss	Output Capacitance				1800		pF
$C_{rss}$	Reverse Transfer Capacitance	7		55		pF	
$R_g$	Gate resistance	f=1MHz		0.8	1.7	2.6	Ω
SWITCH	NG PARAMETERS						
<b>Q</b> <sub>g</sub> (10V)	Total Gate Charge				90	126	nC
$Q_{gs}$	Gate Source Charge	V <sub>GS</sub> =10V, V <sub>DS</sub> =30V, I <sub>D</sub> =20A			20		nC
$Q_{gd}$	Gate Drain Charge				21		nC
Q <sub>oss</sub>	Output Charge	$V_{GS}$ =0V, $V_{DS}$ =30V			110		nC
t <sub>D(on)</sub>	Turn-On DelayTime				19		ns
t <sub>r</sub>	Turn-On Rise Time	$V_{GS}$ =10V, $V_{DS}$ =30V, $R_L$ =1.5 $\Omega$ , $R_{GEN}$ =3 $\Omega$			14		ns
t <sub>D(off)</sub>	Turn-Off DelayTime				70		ns
t <sub>f</sub>	Turn-Off Fall Time				20		ns
t <sub>rr</sub>	Body Diode Reverse Recovery Time	I <sub>F</sub> =20A, di/dt=500A/μs			35		ns
$Q_{rr}$	Body Diode Reverse Recovery Charge	I <sub>F</sub> =20A, di/dt=500A/μs			150		nC

A. The value of  $R_{\text{BJA}}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_{\text{A}}$  =25° C. The Power dissipation  $P_{DSM}$  is based on R  $_{0JA}$  t≤ 10s and the maximum allowed junction temperature of 175  $^{\circ}$  C. The value in any given application depends on the user's specific board design, and the maximum temperature of 175  $^{\circ}$  C may be used if the PCB allows it.

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B. The power dissipation  $P_D$  is based on  $T_{J(MAX)}$ =175° C, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

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C. Single pulse width limited by junction temperature T<sub>J(MAX)</sub>=175° C.

D. The R<sub>BJA</sub> is the sum of the thermal impedance from junction to case R <sub>BJC</sub> and case to ambient.

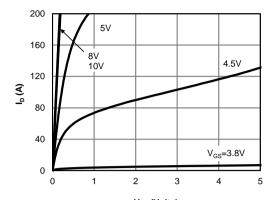
E. The static characteristics in Figures 1 to 6 are obtained using <300µs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of  $T_{J(MAX)}$ =175° C. The SOA curve provides a single pulse rating.

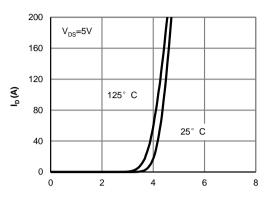
G. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with T<sub>A</sub>=25° C.



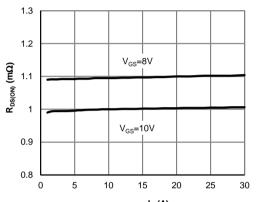
### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



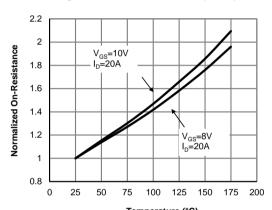
V<sub>DS</sub> (Volts) Figure 1: On-Region Characteristics (Note E)



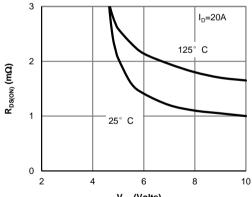
V<sub>GS</sub> (Volts) Figure 2: Transfer Characteristics (Note E)



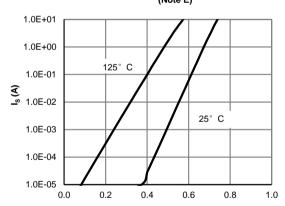
 ${\rm I_D}$  (A) Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)



Temperature (°C)
Figure 4: On-Resistance vs. Junction Temperature
(Note E)



V<sub>GS</sub> (Volts)
Figure 5: On-Resistance vs. Gate-Source Voltage
(Note E)



V<sub>SD</sub> (Volts) Figure 6: Body-Diode Characteristics (Note E)

100

10



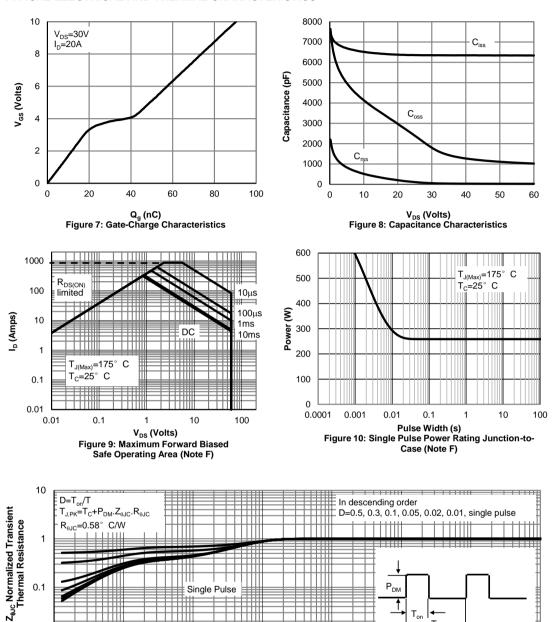
0.01

1E-05

0.0001

0.001

#### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



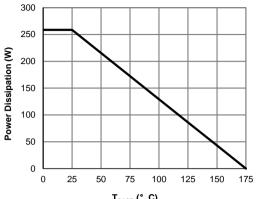
Pulse Width (s)
Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

0.1

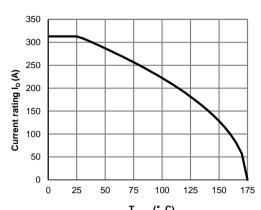
0.01



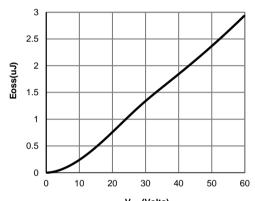
#### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



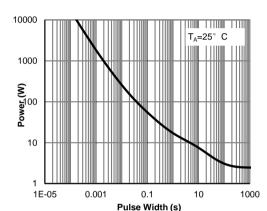
T<sub>CASE</sub> (° C)
Figure 12: Power De-rating (Note F)



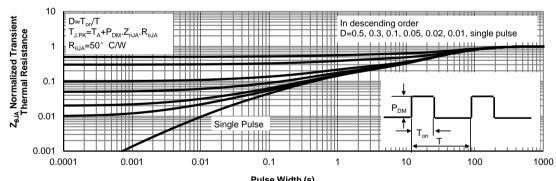
T<sub>CASE</sub> (° C)
Figure 13: Current De-rating (Note F)



V<sub>DS</sub> (Volts) Figure 14: Coss stored Energy



Pulse Width (s) Figure 15: Single Pulse Power Rating Junction-to-Ambient (Note G)



Pulse Width (s)
Figure 16: Normalized Maximum Transient Thermal Impedance (Note G)

Figure A: Gate Charge Test Circuit & Waveforms

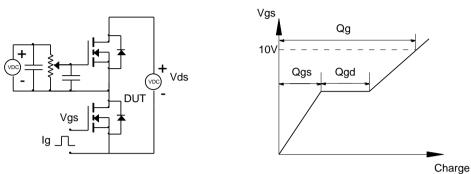


Figure B: Resistive Switching Test Circuit & Waveforms

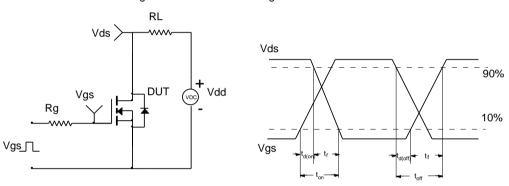


Figure C: Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

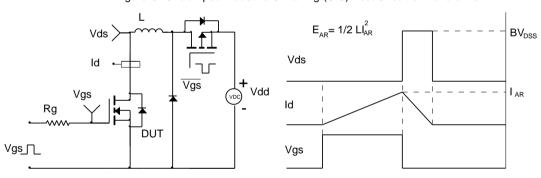


Figure D: Diode Recovery Test Circuit & Waveforms

